

# ECE 538: VLSI System Testing

## Assignment 4

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### **Duke Community Standard**

By submitting this L<sup>A</sup>T<sub>E</sub>X document, I affirm that

1. I have adhered to the Duke Community Standard in completing this assignment.

## Problem 1 Path Delay and Small Delay Defect Testing using Synopsys TetraMax:

### a. Path Delay Faults

(i)

Number of Critical Paths	50	100	150	200	250	300
Total Faults	50	100	150	200	250	300
Detected	44	82	123	128	129	128
Test Coverage	88.00%	82.00%	82.00%	64.00%	51.60%	42.67%
Patterns	9	18	19	19	19	18
CPU Time	0.02	0.02	0.03	0.02	0.03	0.05

Table 1: Results for path-delay faults, 0.15ns clock period

(ii)

Number of Critical Paths	50	100	150	200	250	300
Total Faults	50	100	150	200	250	300
Detected	44	82	123	128	129	128
Test Coverage	88.00%	82.00%	82.00%	64.00%	51.60%	42.67%
Patterns	9	18	19	18	19	18
CPU Time	0.01	0.03	0.03	0.03	0.03	0.04

Table 2: Results for path-delay faults, 0.10ns clock period

### b. Small Delay Defects

(i)

Slack	10%	15%	20%	25%	30%
Total Faults	4094	4094	4094	4094	4094
Detected	3994	3994	3994	3994	3994
Delay Effectiveness	0.11ns(55.17%)	0.165ns(30.75%)	0.22ns(50.08%)	0.275ns(49.82%)	0.33ns(53.68%)
SDQL	6289088.50	6126893.50	5438607.50	4897204.50	4477742.50
CPU Time	0.07	0.07	0.07	0.08	0.08

Table 3: Results for small delay defects, 1.1ns clock period

(ii)

Slack	10%	15%	20%	25%	30%
Total Faults	4094	4094	4094	4094	4094
Detected	3994	3994	3994	3994	3994
Delay Effectiveness	0.12ns(6.64%)	0.18ns(49.23%)	0.24ns(25.95%)	0.30ns(44.24%)	0.36ns(49.65%)
SDQL	5756102.00	5206344.50	5301291.50	4501716.00	4122875.25
CPU Time	0.08	0.06	0.07	0.07	0.08

Table 4: Results for small delay defects, 1.2ns clock period

(iii)

Slack	10%	15%	20%	25%	30%
Total Faults	4094	4094	4094	4094	4094
Detected	3994	3994	3994	3994	3994
Delay Effectiveness	0.10ns(44.24%)	0.15ns(45.63%)	0.20ns(50.85%)	0.25ns(51.03%)	0.30ns(58.95%)
SDQL	6445672.00	5683769.50	5567790.00	5023122.00	4668992.50
CPU Time	0.07	0.08	0.08	0.08	0.08

Table 5: Results for small delay defects, 1.0ns clock period